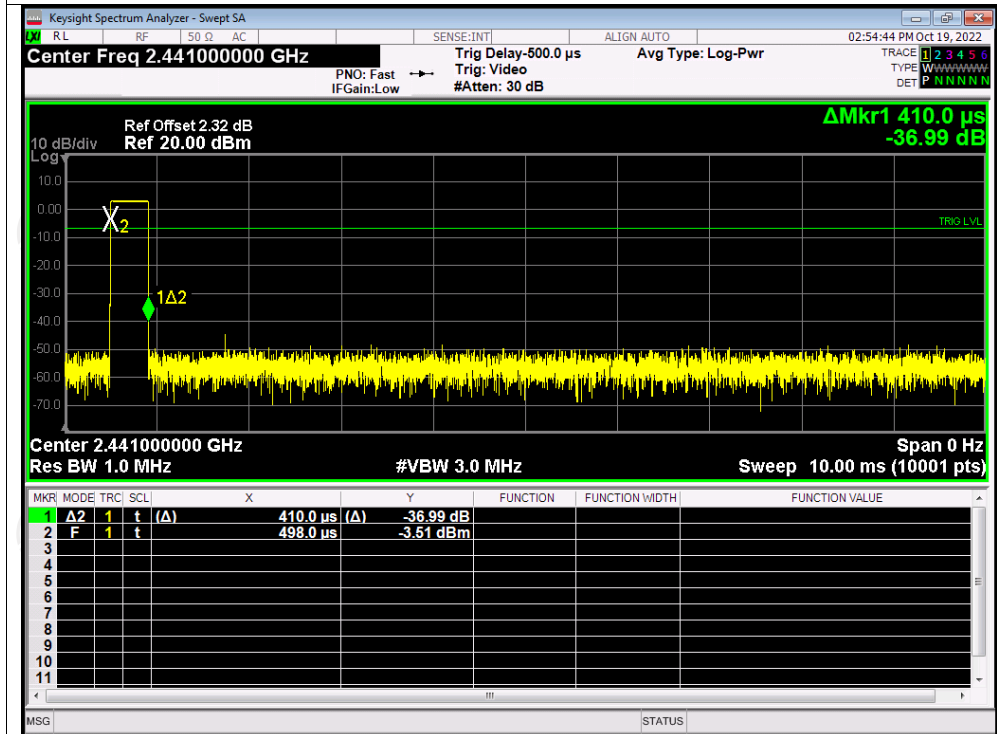


Dwell Time

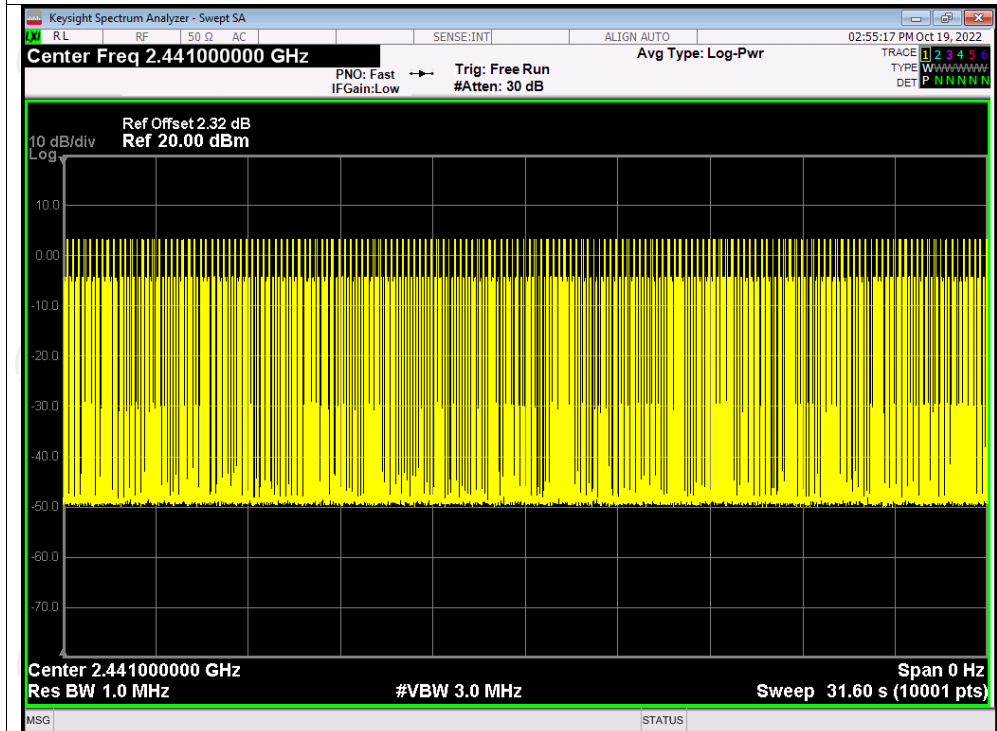
Condition	Mode	Frequency (MHz)	Pulse Time (ms)	Total Dwell Time (ms)	Burst Count	Period Time (ms)	Limit (ms)	Verdict
NVNT	1-DH1	2441	0.41	130.79	319	31600	400	Pass
NVNT	1-DH3	2441	1.66	265.60	160	31600	400	Pass
NVNT	1-DH5	2441	2.91	314.28	108	31600	400	Pass
NVNT	2-DH1	2441	0.40	126.80	317	31600	400	Pass
NVNT	2-DH3	2441	1.65	272.25	165	31600	400	Pass
NVNT	2-DH5	2441	2.90	333.50	115	31600	400	Pass
NVNT	3-DH1	2441	0.40	127.60	319	31600	400	Pass
NVNT	3-DH3	2441	1.65	272.25	165	31600	400	Pass
NVNT	3-DH5	2441	2.90	339.30	117	31600	400	Pass

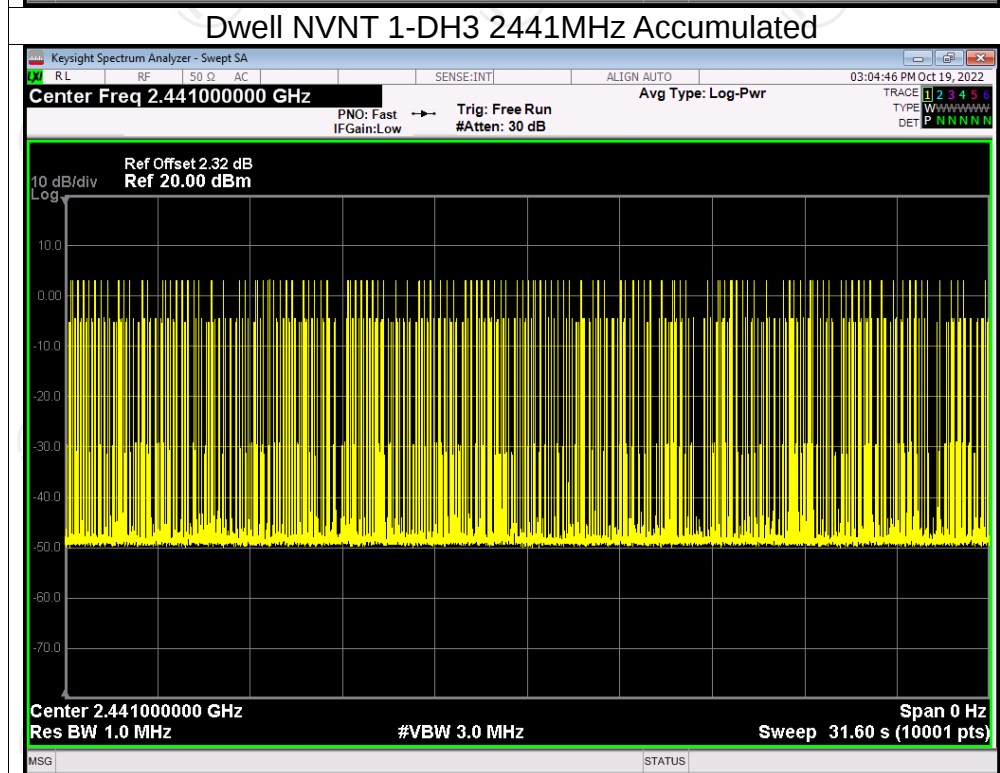
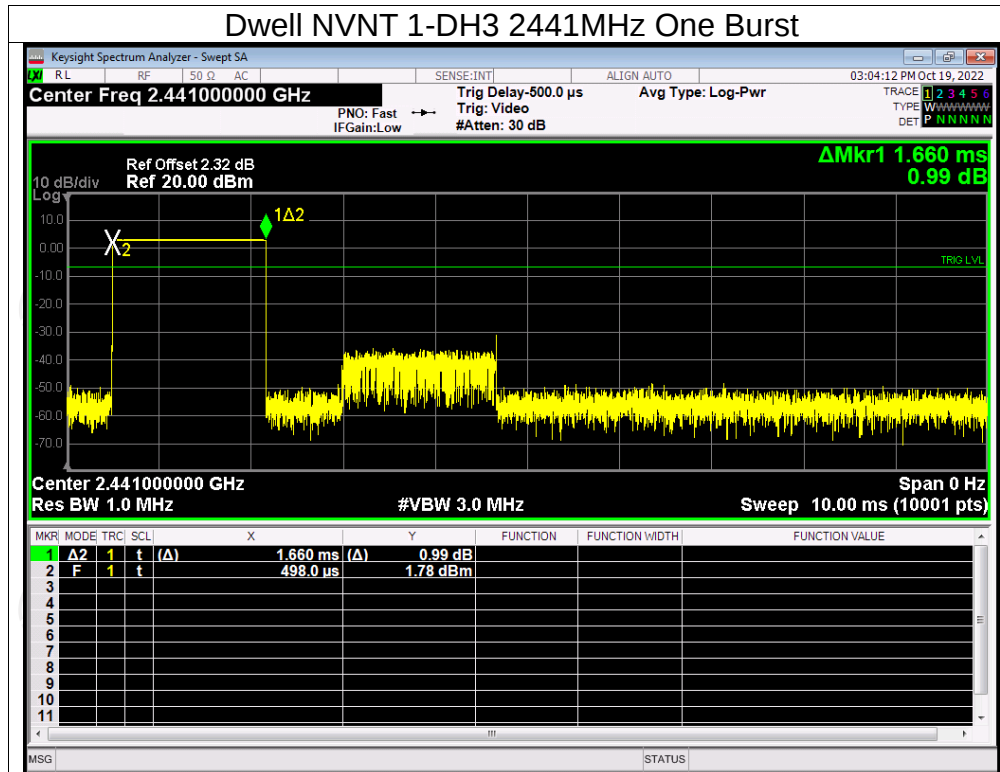
Test Graphs

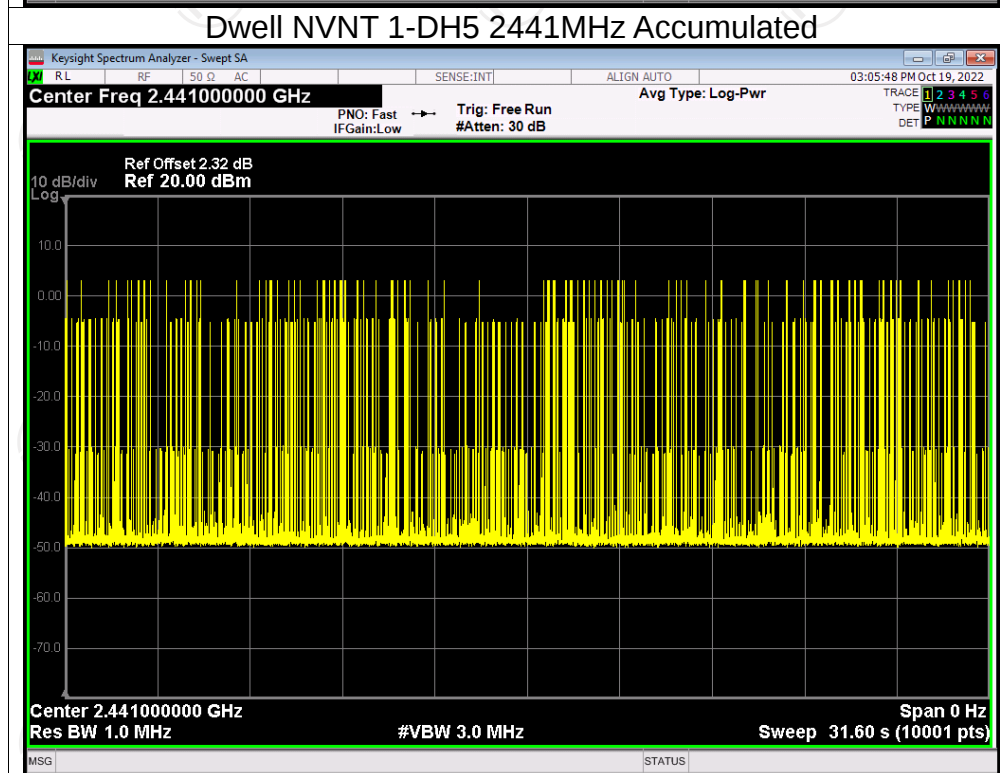
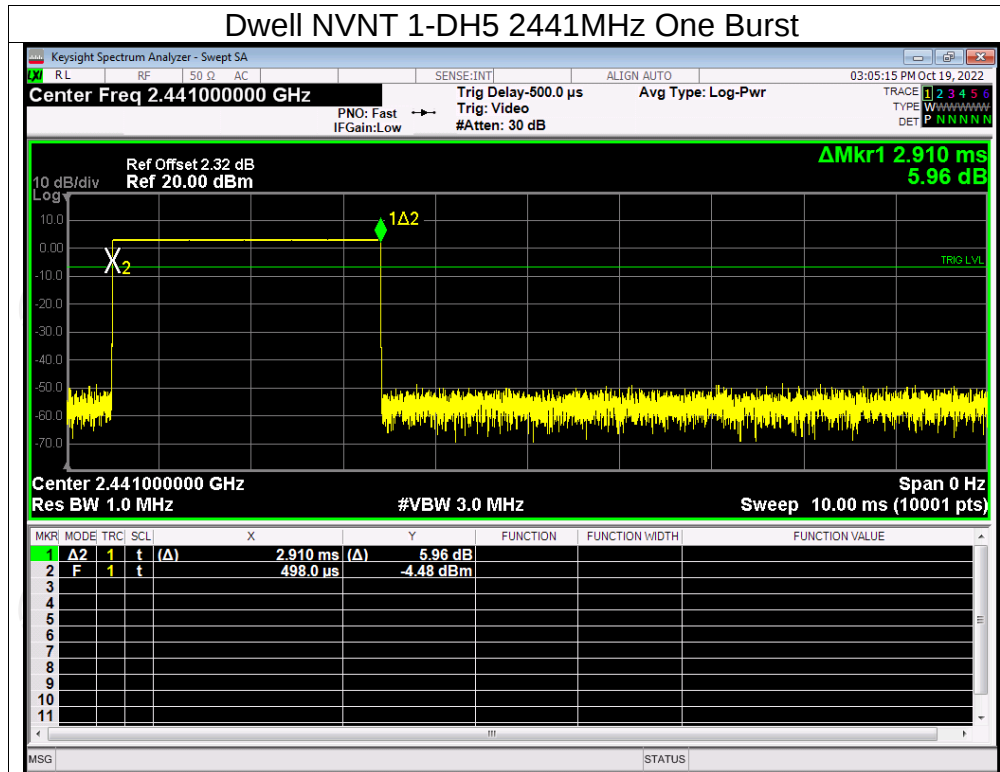
Dwell NVNT 1-DH1 2441MHz One Burst

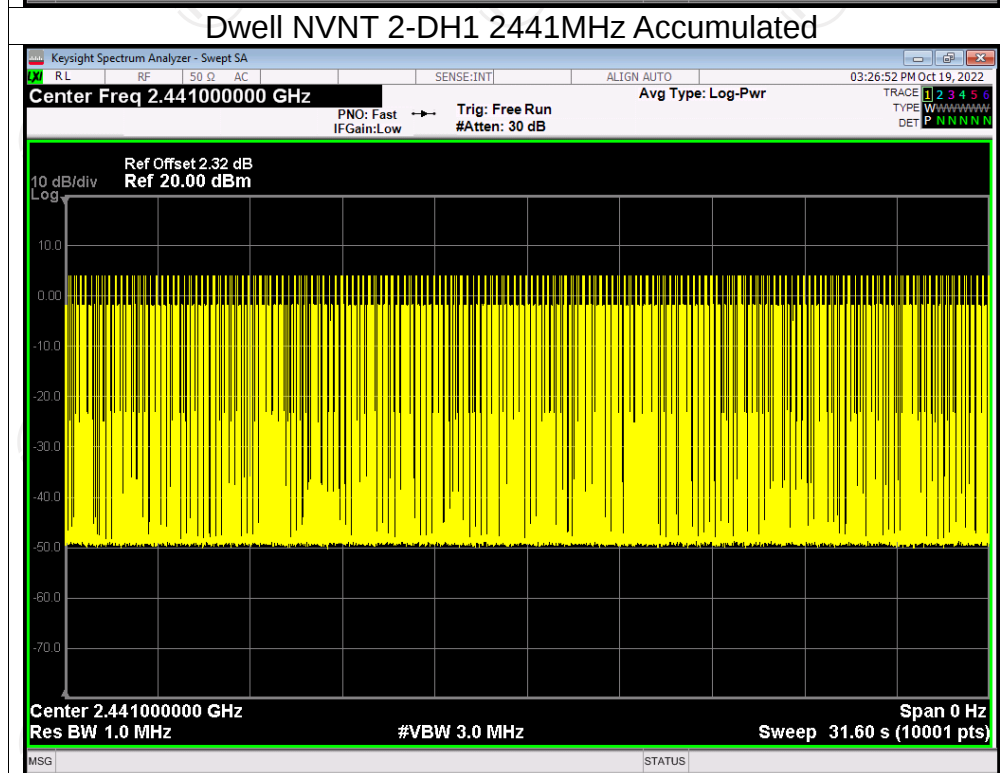
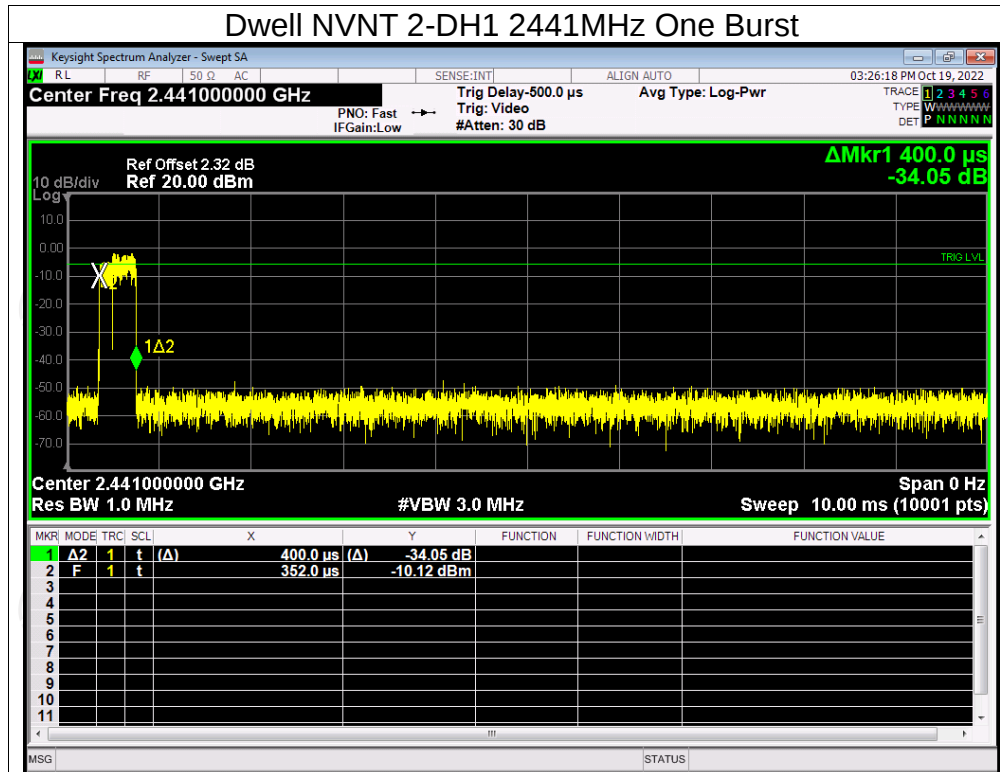


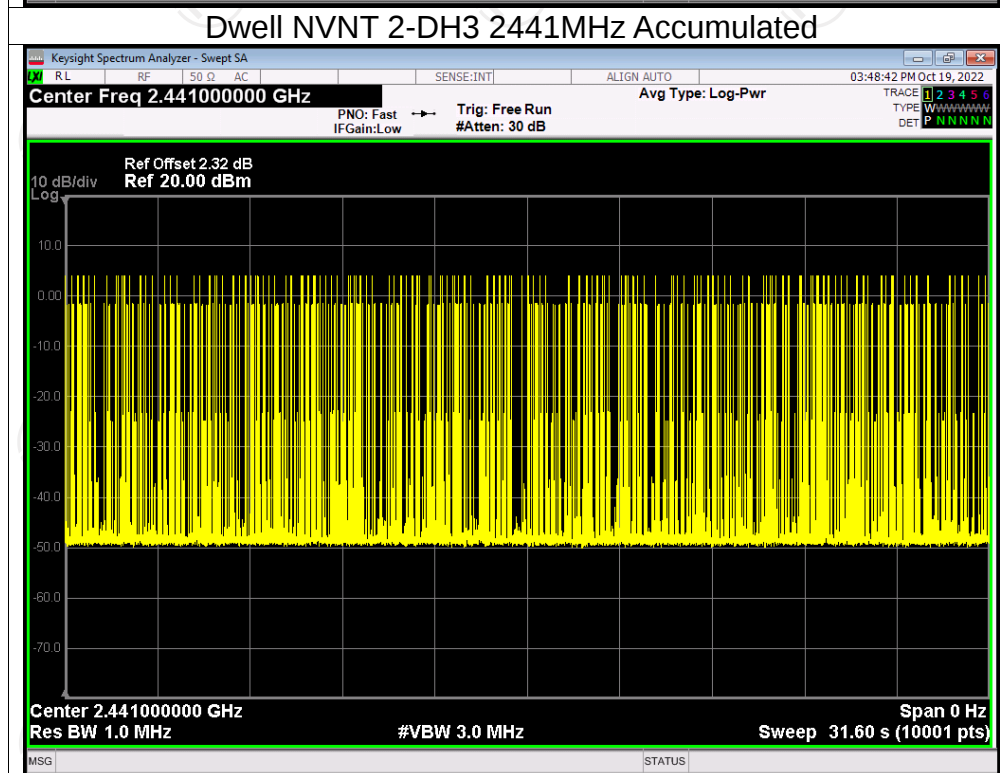
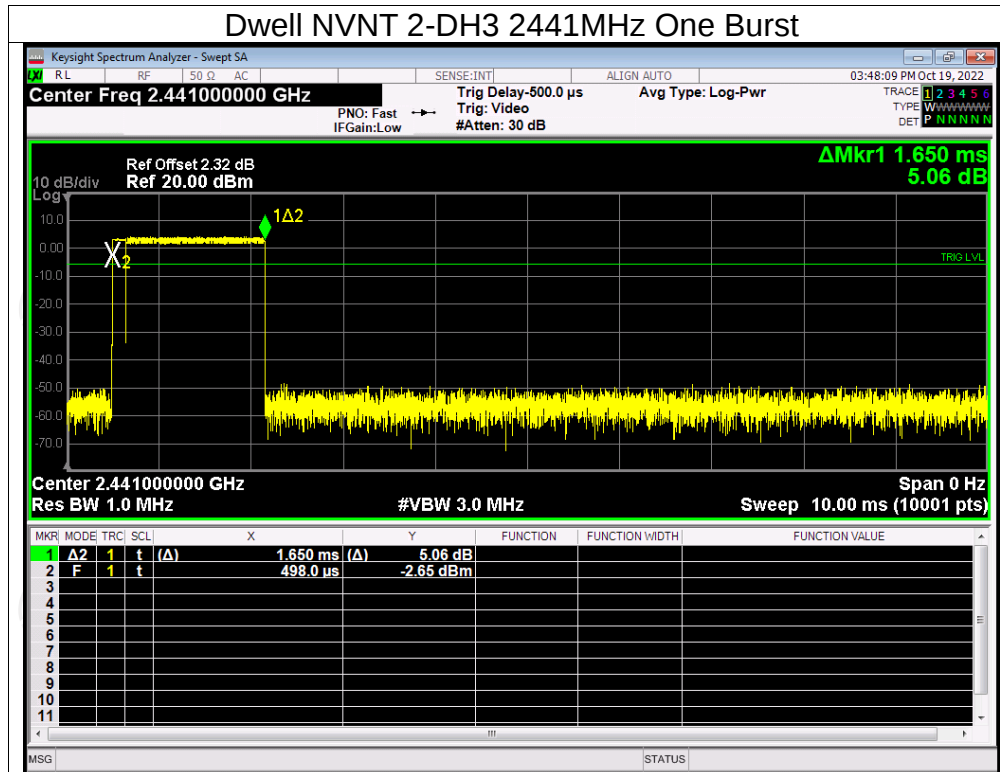
Dwell NVNT 1-DH1 2441MHz Accumulated

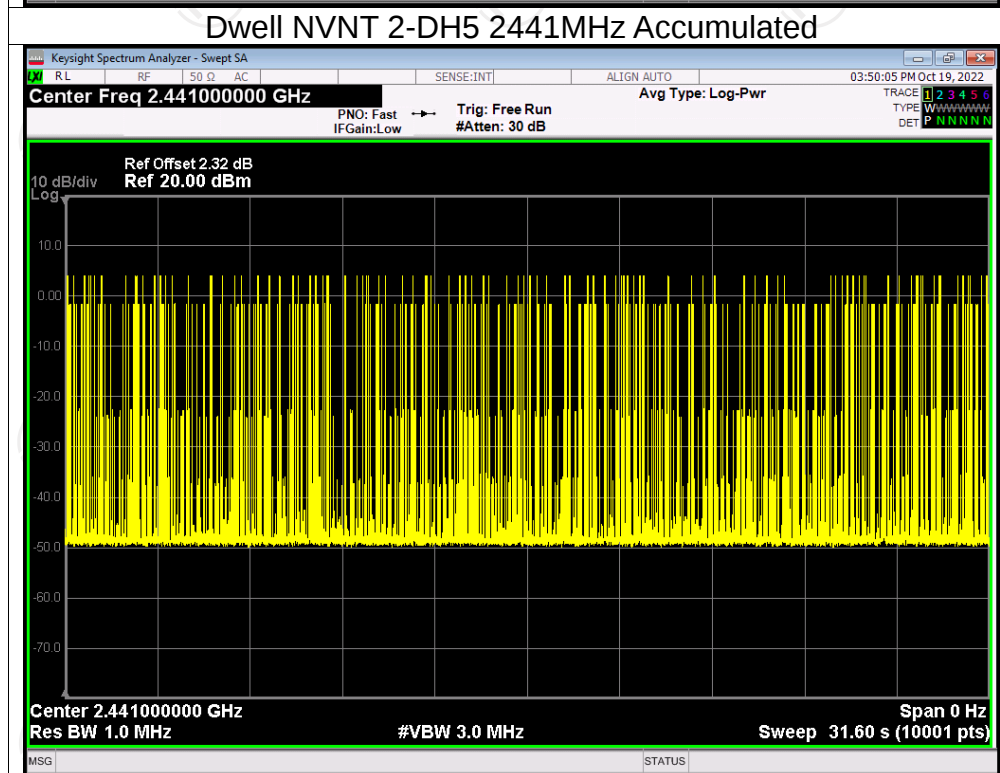
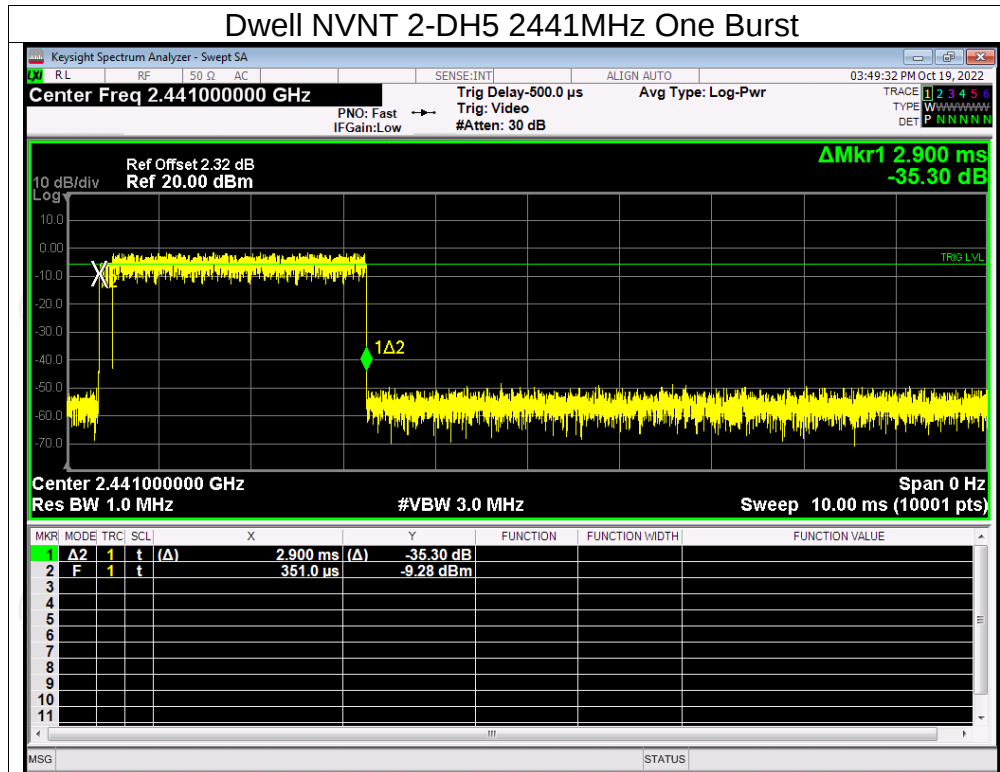


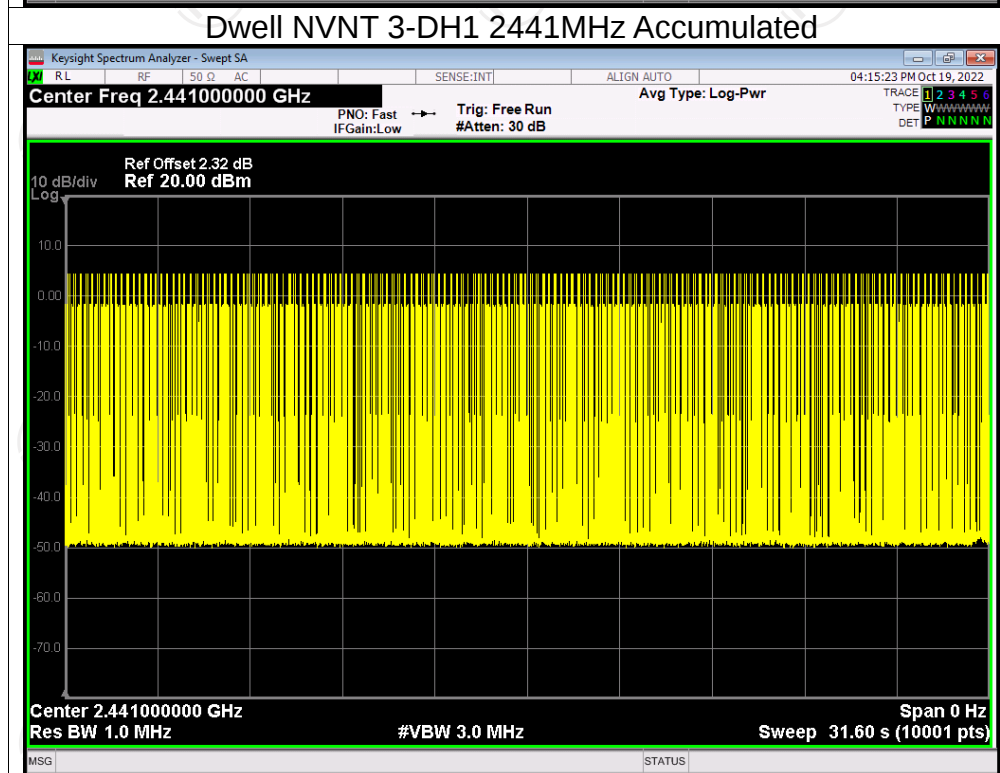
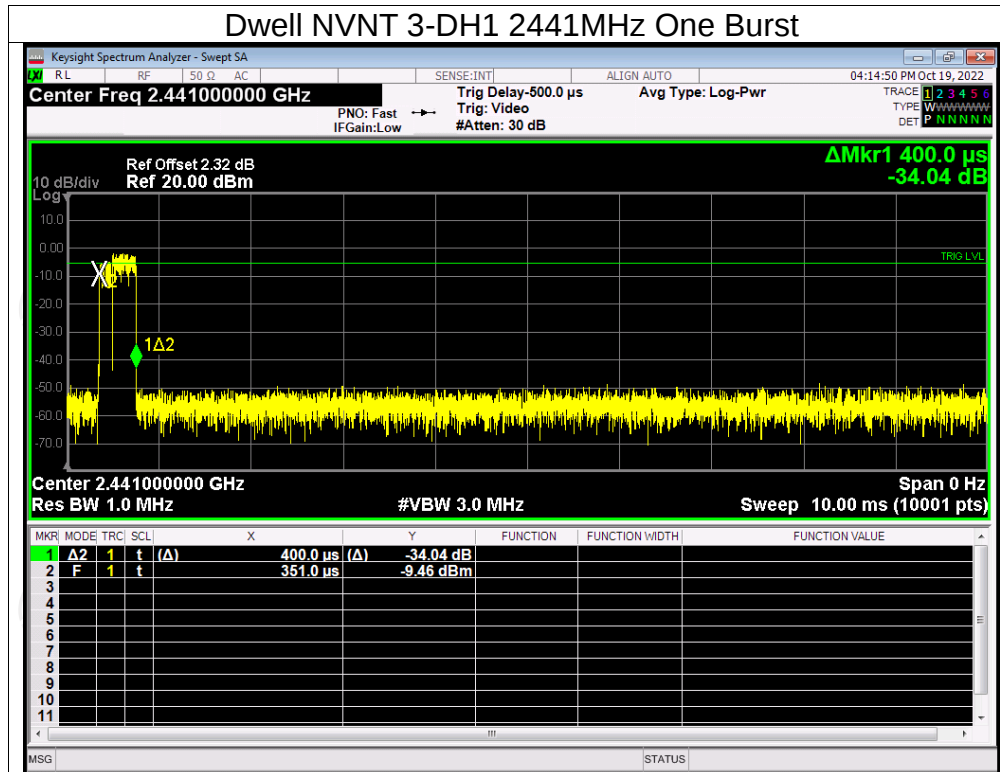


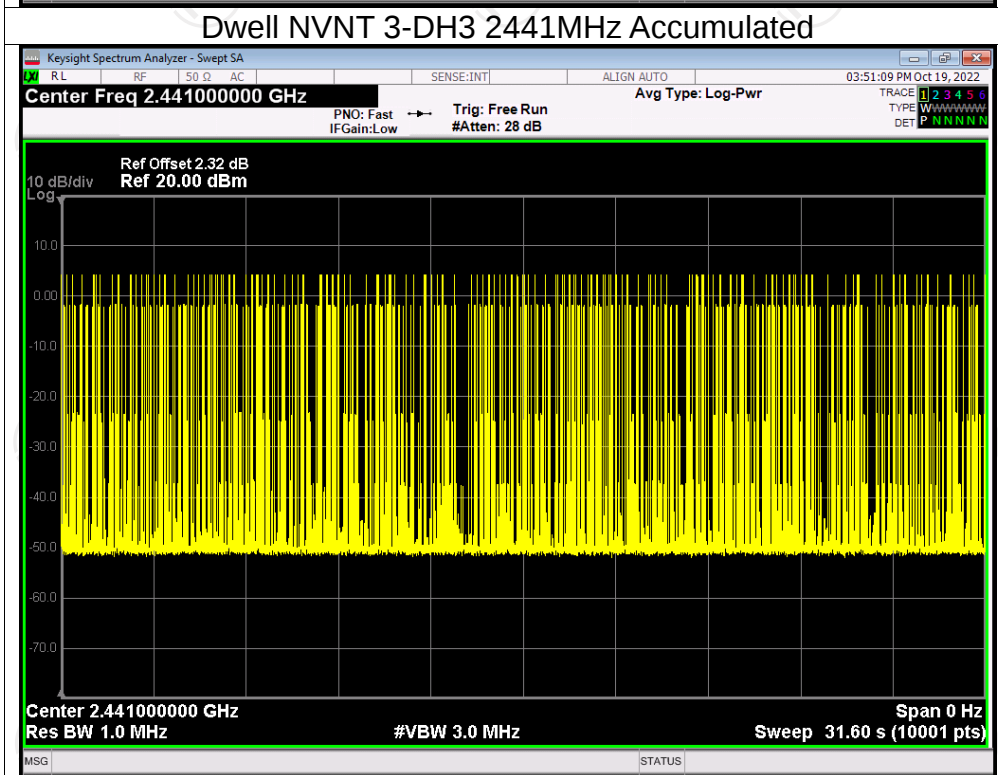
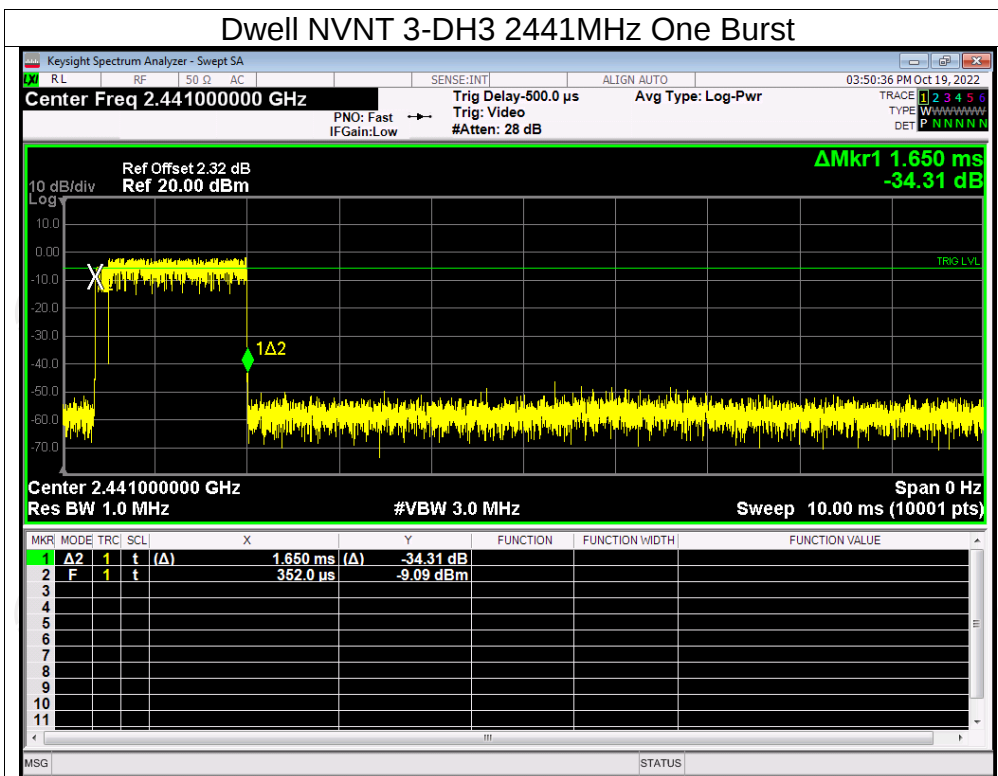


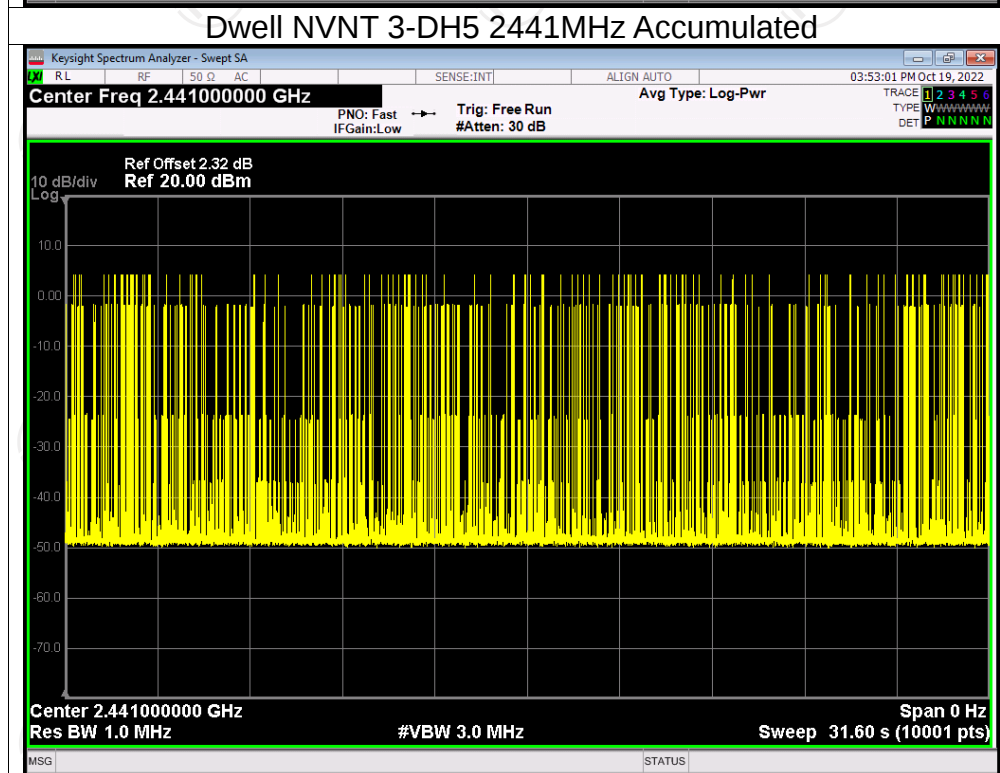
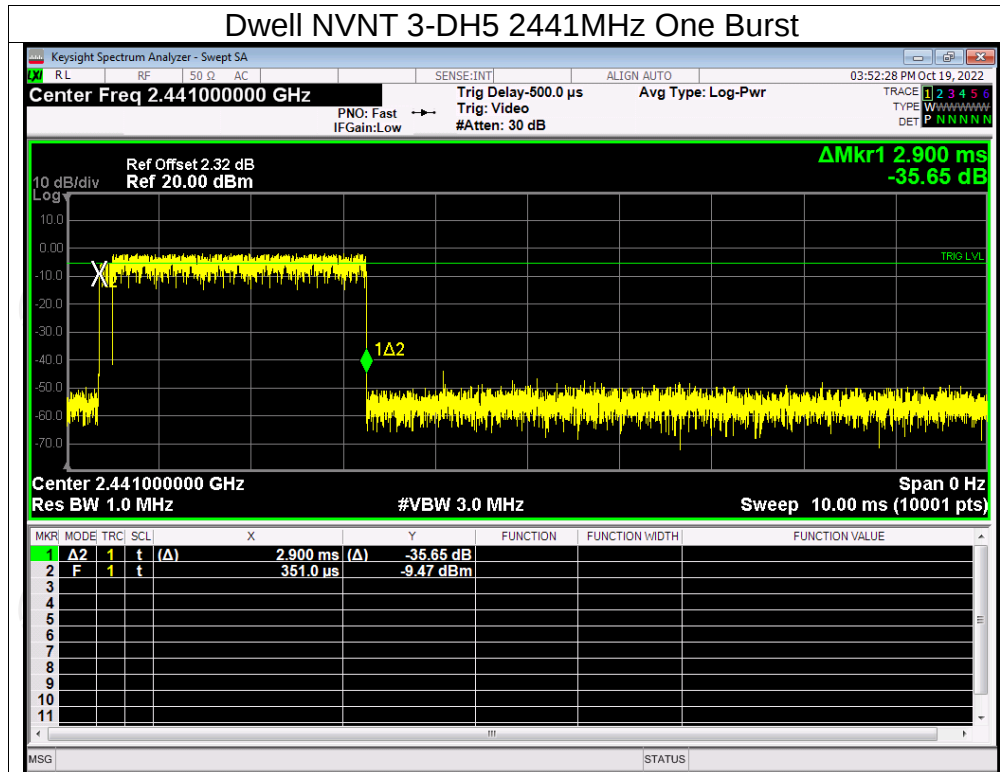










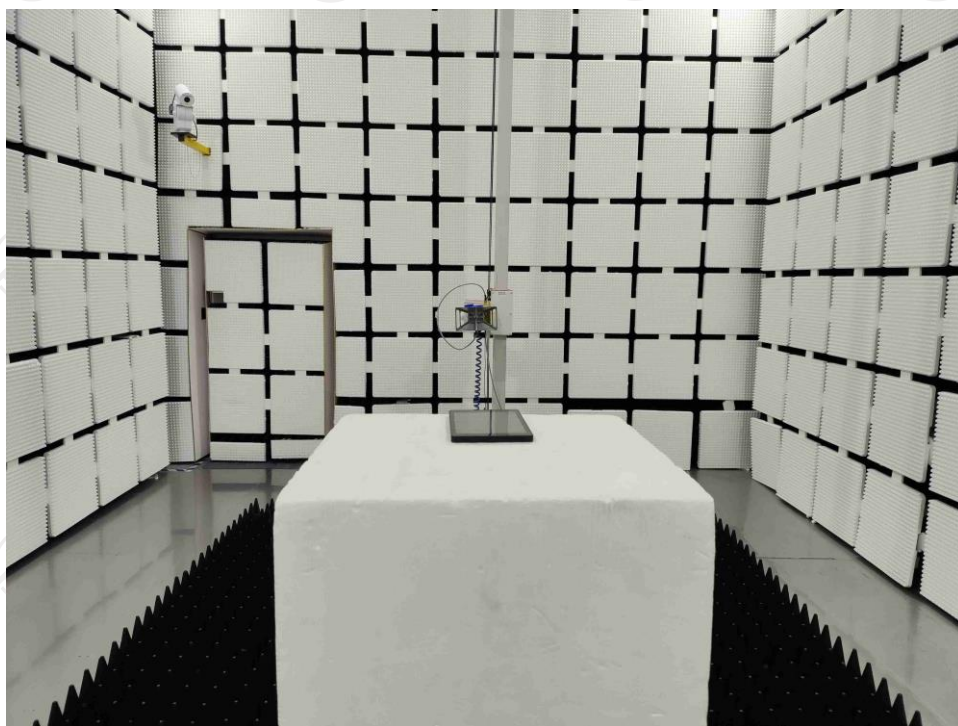
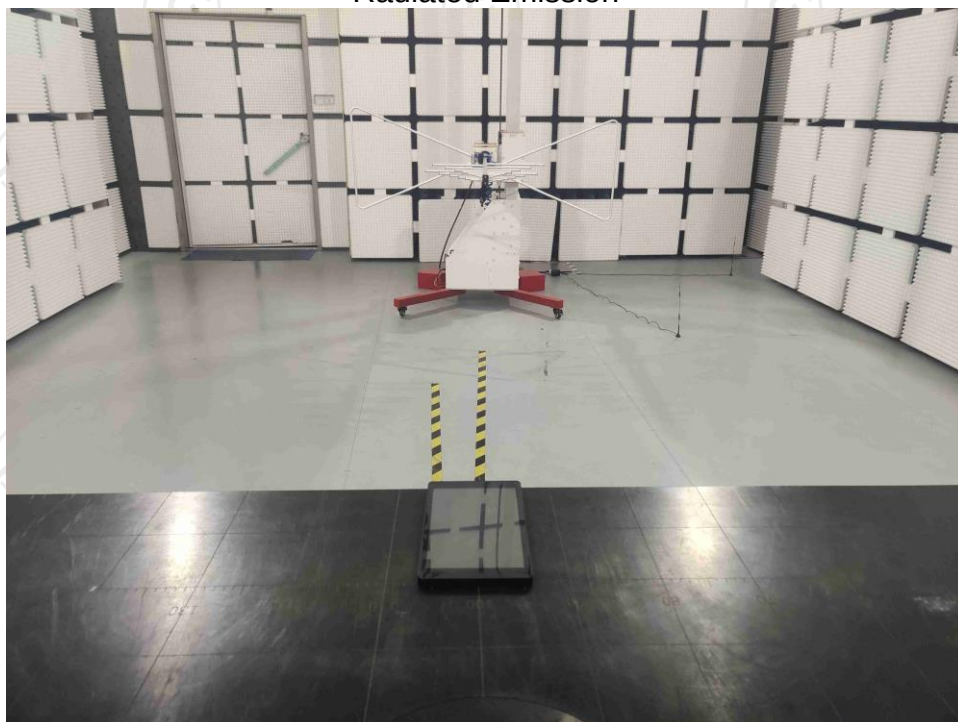


Appendix B: Photographs of Test Setup

Product: LTE Tablet

Model: X8ULTRA

Radiated Emission



Conducted Emission

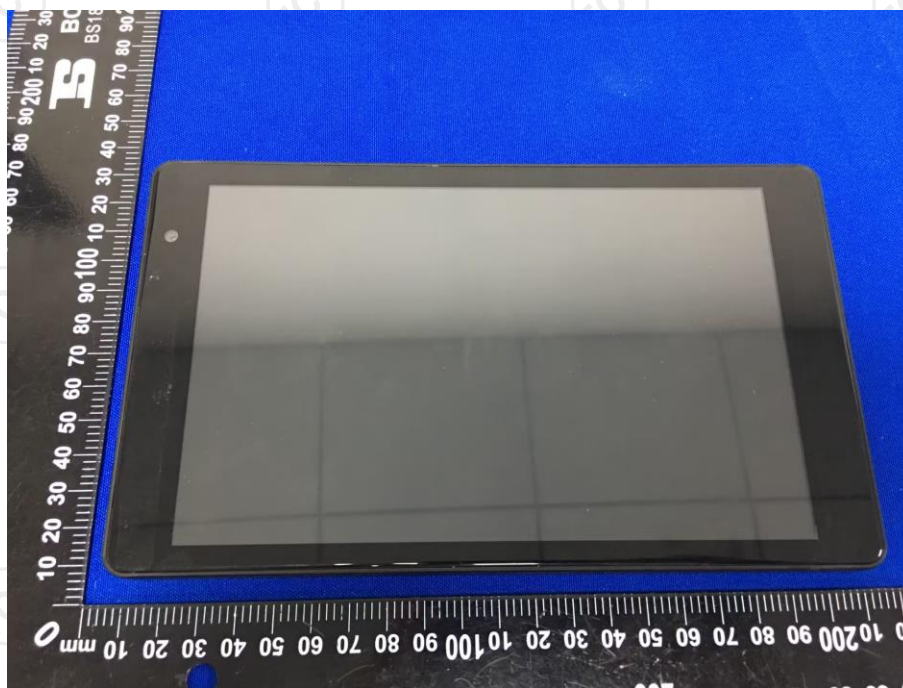
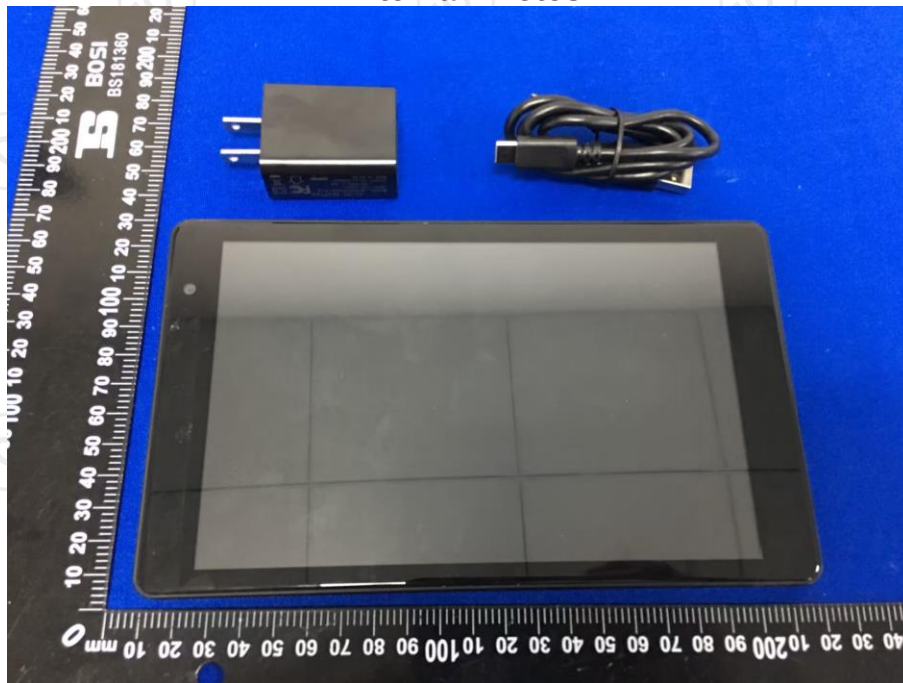


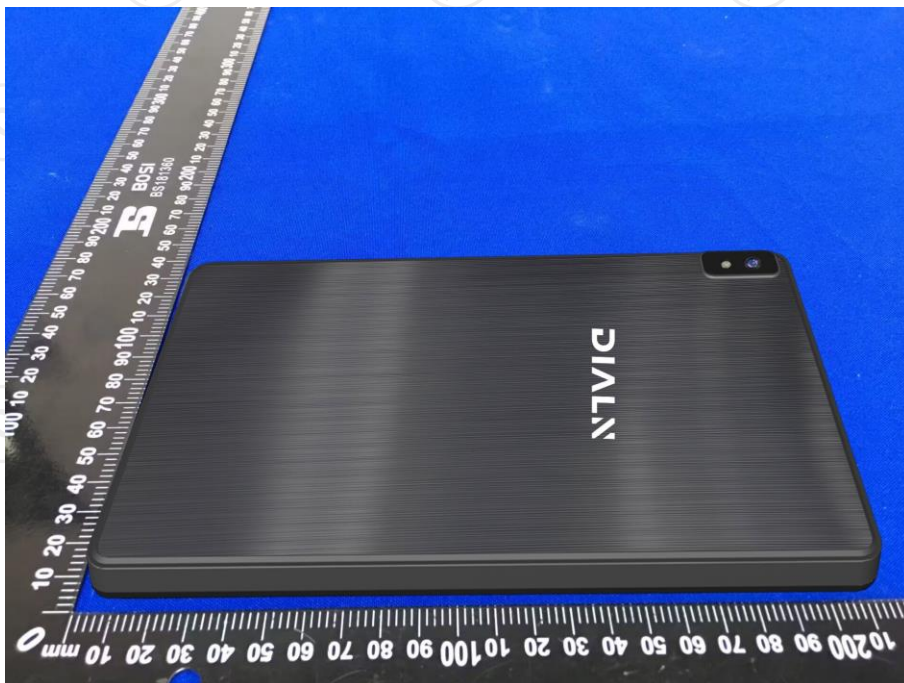
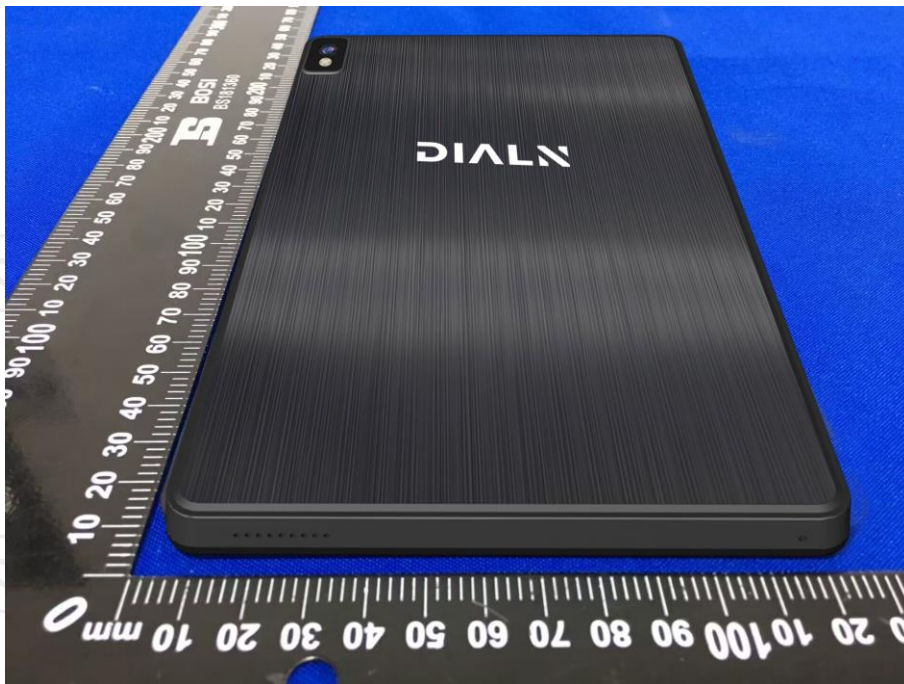
Appendix C: Photographs of EUT

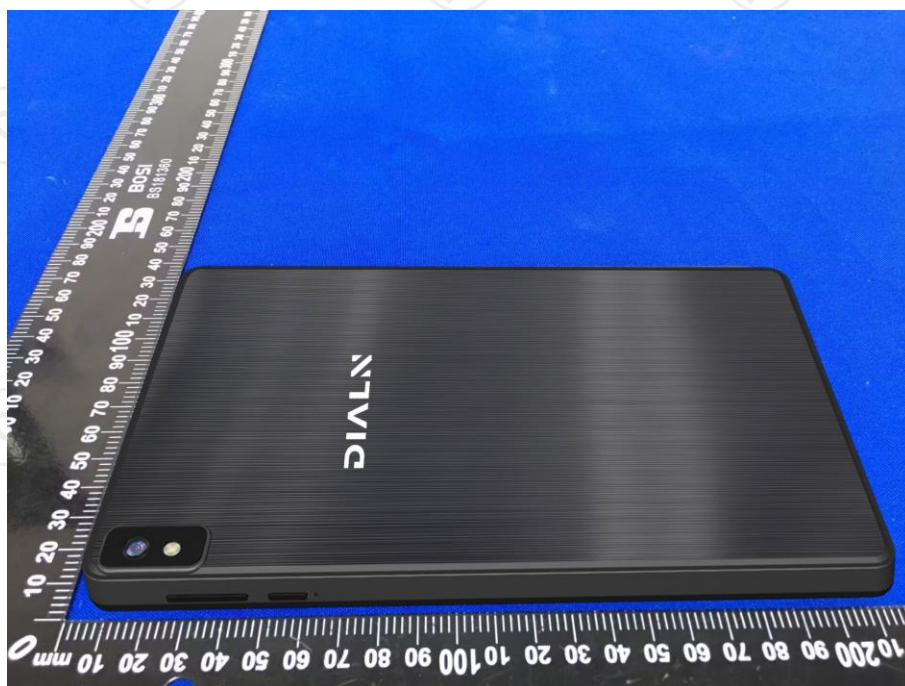
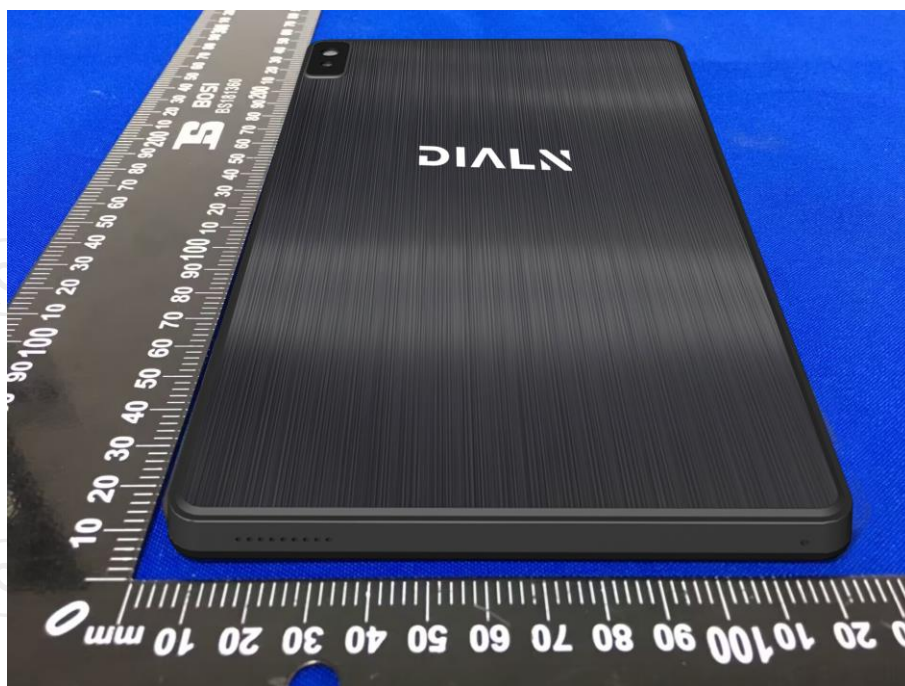
Product: LTE Tablet

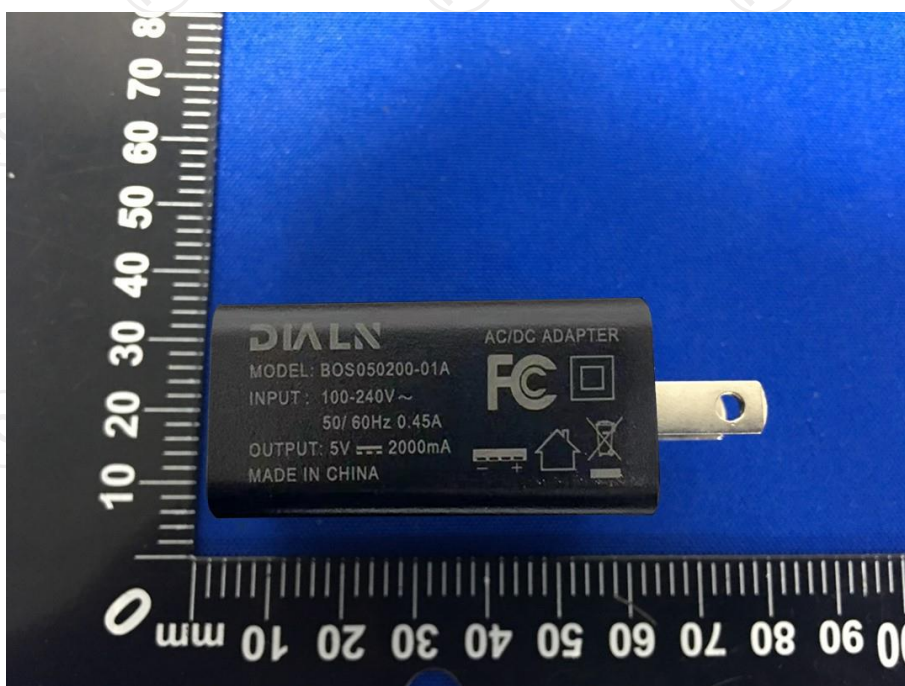
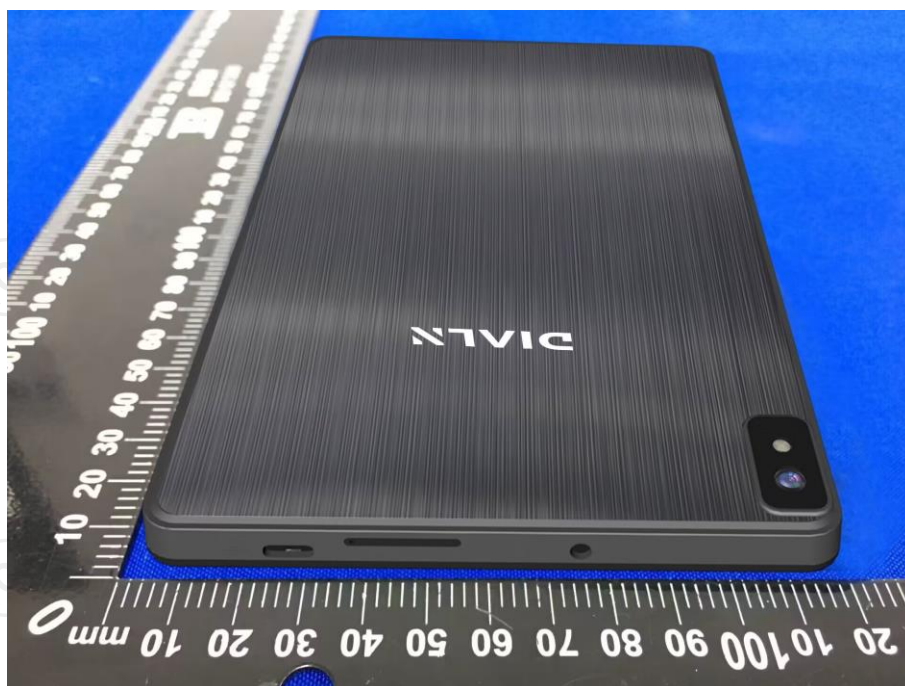
Model: X8ULTRA

External Photos

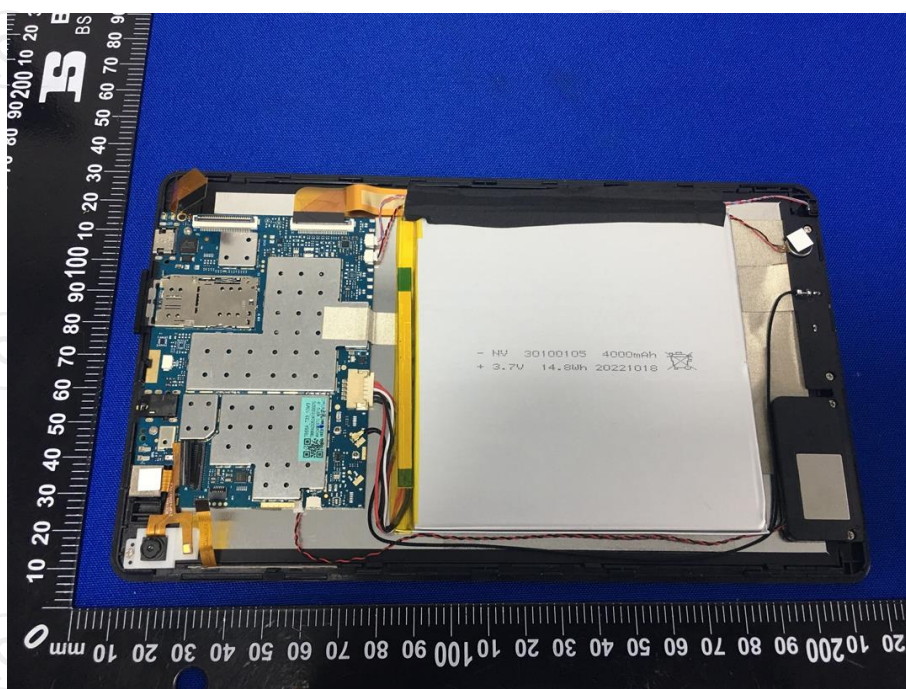


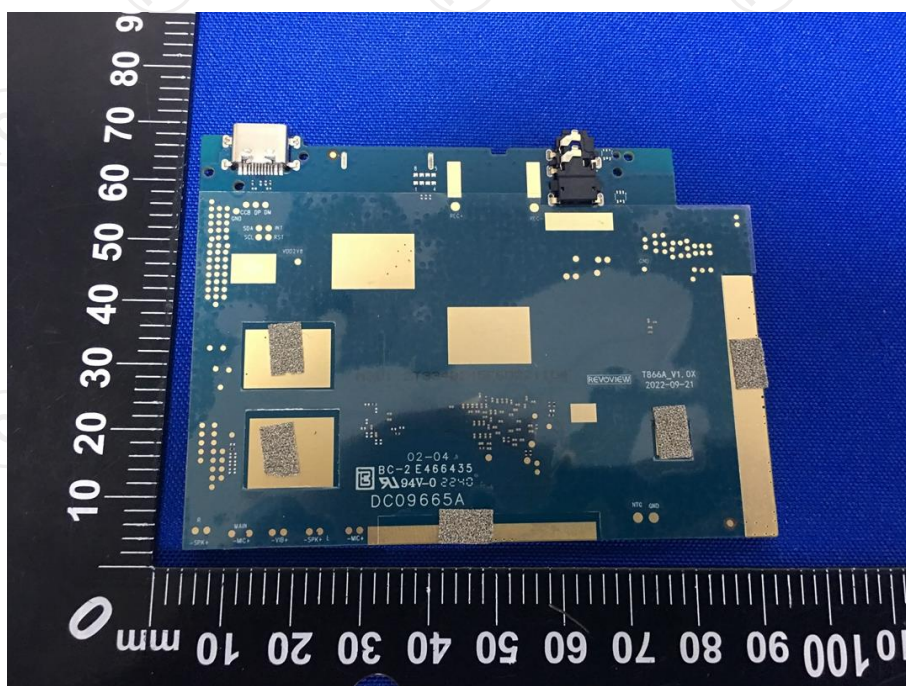
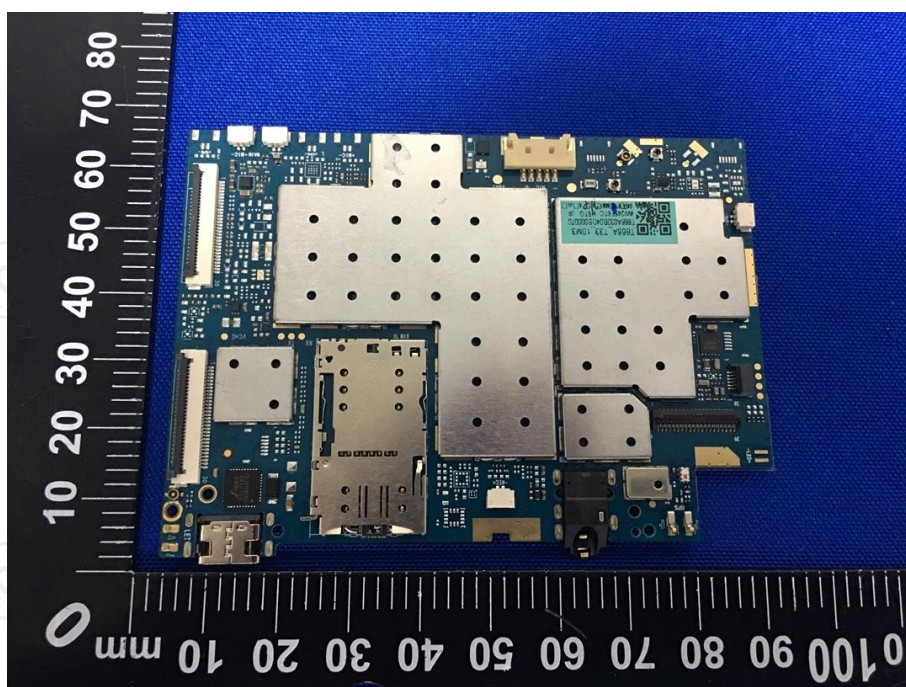


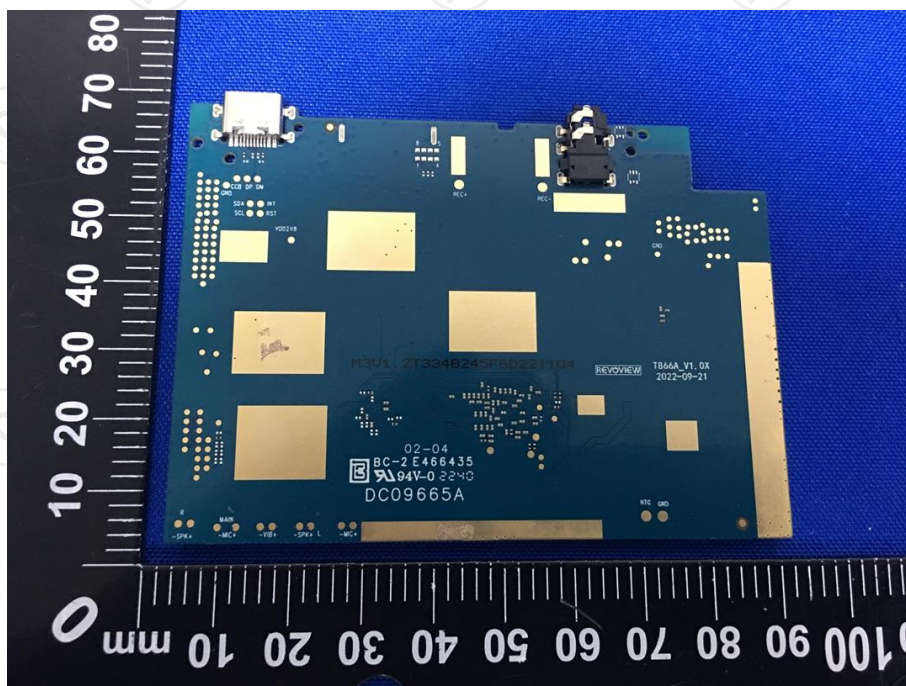
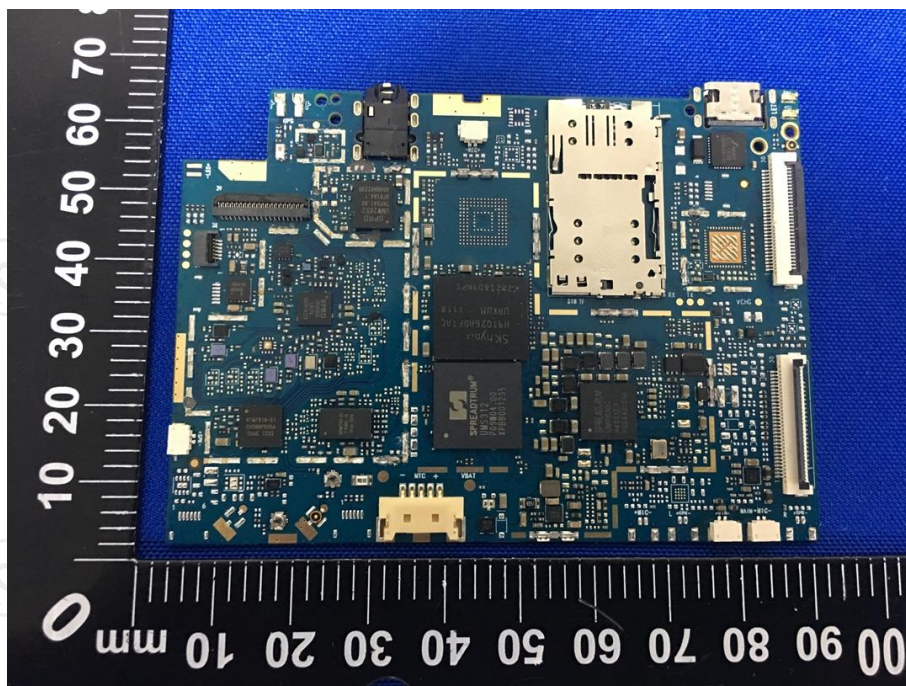


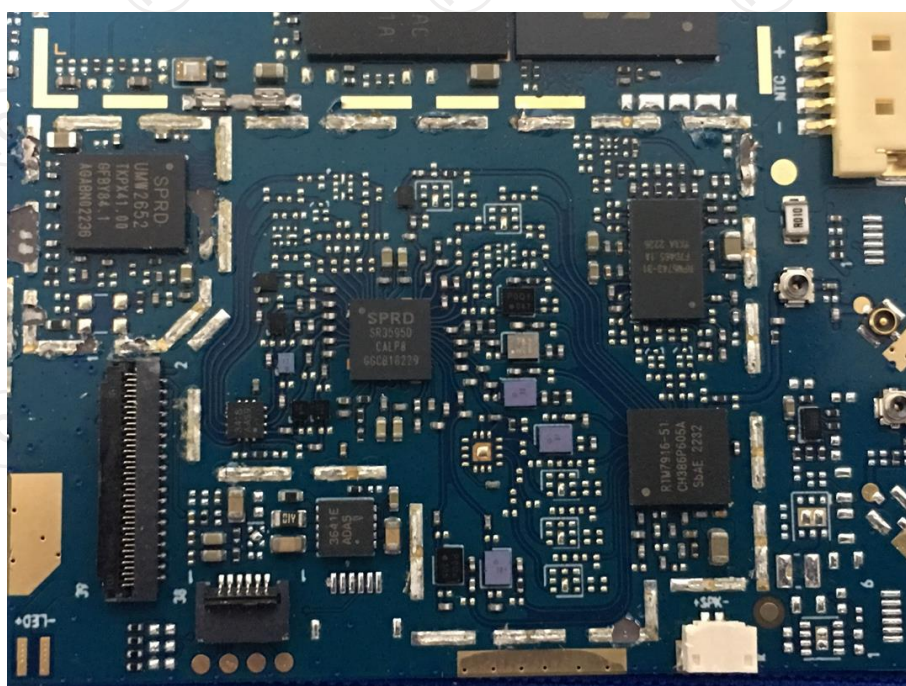
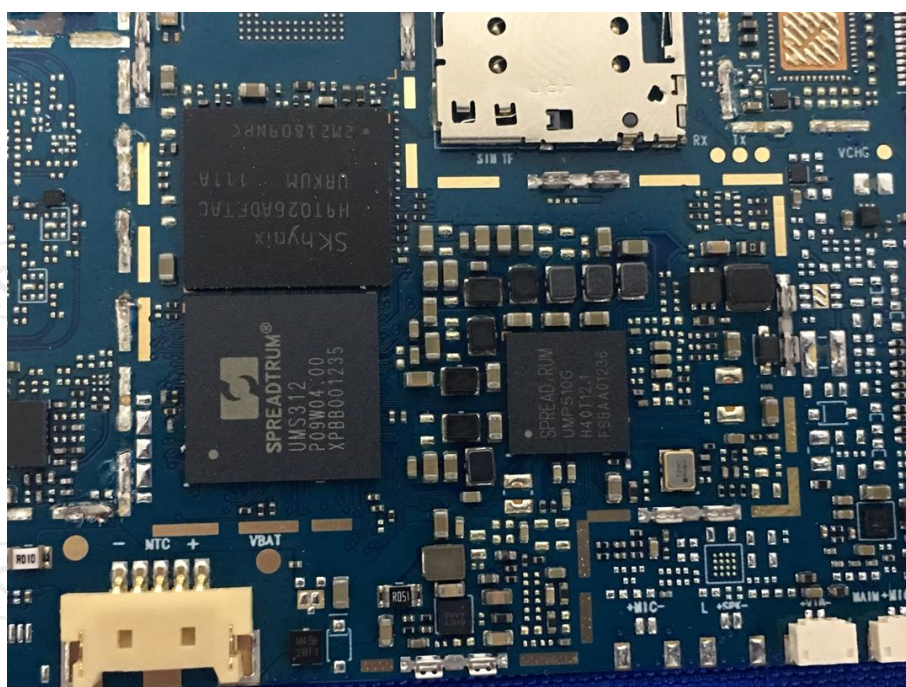


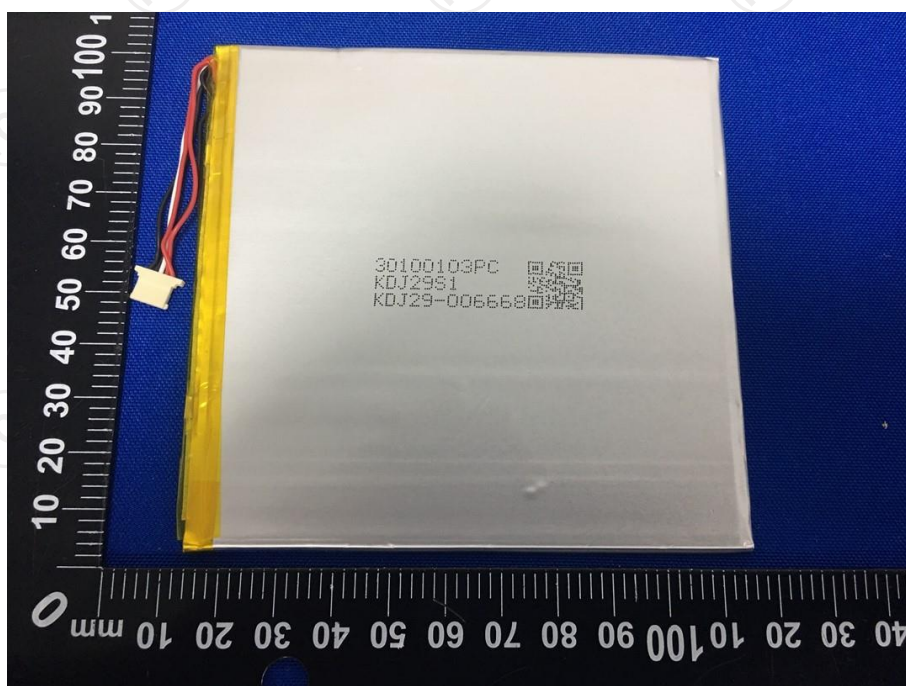
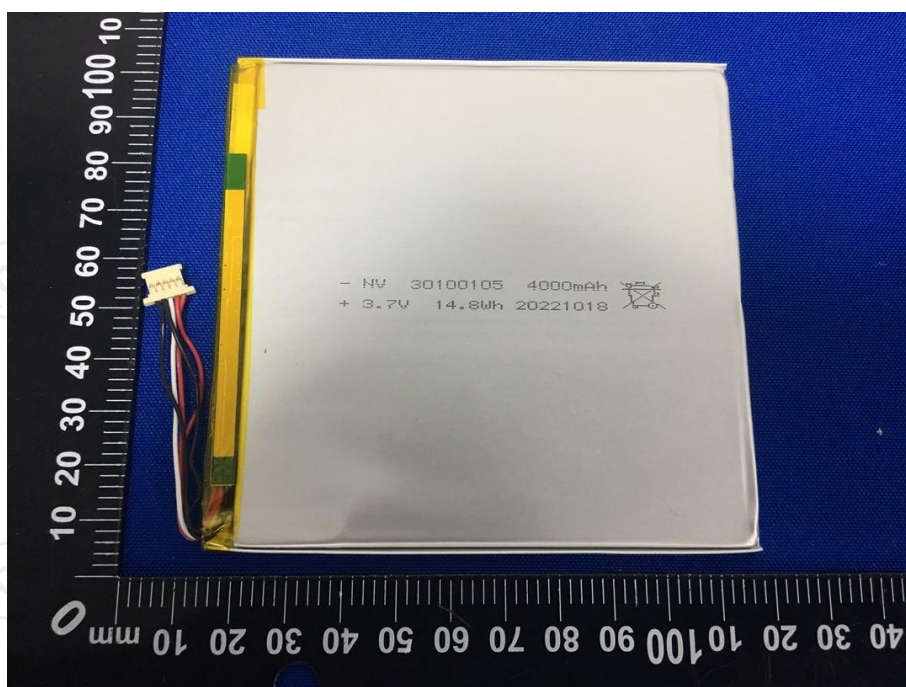
Product: LTE Tablet
Model: X8ULTRA
Internal Photos











*******END OF REPORT*******